

<b>Notice of References Cited</b>	Application/Control No. 10/813,898	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner /Yonel Beaulieu/	Art Unit 3661	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,695,108	02-2004	Hanke et al.	192/3.29
*	C	US-6,110,068	08-2000	Kraska, Marvin Paul	475/146
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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